Abstracts

Characterization of Microwave Oscillator and Amplifier Circuits Using an IMPATT Diode Biased Below Breakdown (Short Papers)

R.C. Tozer, R. Charlton and G.S. Hobson. "Characterization of Microwave Oscillator and Amplifier Circuits Using an IMPATT Diode Biased Below Breakdown (Short Papers)." 1974 Transactions on Microwave Theory and Techniques 22.8 (Aug. 1974 [T-MTT]): 806-808.

A convenient laboratory technique is described to measure the internal circuit loss, the load conductance, and equivalent circuit susceptances of microwave diode oscillators and amplifiers using an IMPATT diode biased just below its breakdown voltage.

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